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ON Semiconductor®

# FDG6332C-F085

# 20V N & P-Channel PowerTrench® MOSFETs

#### **Features**

• Q1 0.7 A, 20V.  $R_{DS(ON)} = 300 \text{ m}\Omega \ @ \ V_{GS} = 4.5 \text{ V}$   $R_{DS(ON)} = 400 \text{ m}\Omega \ @ \ V_{GS} = 2.5 \text{ V}$ 

• **Q2** -0.6 A, -20V.  $R_{DS(ON)} = 420$  m $\Omega$  @  $V_{GS} = -4.5$  V  $R_{DS(ON)} = 630$  m $\Omega$  @  $V_{GS} = -2.5$  V

- · Low gate charge
- High performance trench technology for extremely low R<sub>DS(ON)</sub>
- SC70-6 package: small footprint (51% smaller than SSOT-6); low profile (1mm thick)
- Qualified to AEC Q101
- RoHS Compliant

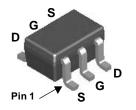
#### **General Description**

The N & P-Channel MOSFETs are produced using ON Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance.

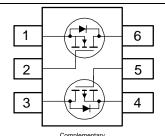
These devices have been designed to offer exceptional power dissipation in a very small footprint for applications where the bigger more expensive TSSOP-8 and SSOP-6 packages are impractical.

#### **Applications**

- DC/DC converter
- · Load switch
- · LCD display inverter



SC70-6



**Absolute Maximum Ratings** T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Q1	Q2	Units
V <sub>DSS</sub>	Drain-Source Voltage		20	-20	V
V <sub>GSS</sub>	Gate-Source Voltage		±12	±12	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1)	0.7	-0.6	А
	- Pulsed		2.1	-2	
$P_D$	Power Dissipation for Single Operation (Note 1)		0	W	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperat	–55 to	°C		

#### **Thermal Characteristics**

R <sub>0JA</sub> Thermal Resistance, Junction-to-Ambient (Note 1)	415	°C/W
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#### **Package Marking and Ordering Information**

Device Marking	Device	Device Reel Size Tape width		Quantity
.32	FDG6332C-F085	7"	8mm	3000 units

Symbol	Parameter		Test Conditions	M	lin	Тур	Max	Units
Off Char	acteristics							
BV <sub>DSS</sub>	Drain-Source Breakdown Volta	ge	$V_{GS} = 0 \text{ V}, \qquad I_D = 250 \mu\text{A} $ $V_{GS} = 0 \text{ V}, \qquad I_D = -250 \mu\text{A} $ <b>Q</b>		20 20			V
<u>ΔBVpss</u> ΔT <sub>J</sub>	Breakdown Voltage Temperatur Coefficient	re	$I_D = 250 \mu A, Ref. to 25^{\circ}C$ Q $I_D = -250 \mu A, Ref. to 25^{\circ}C$ Q			14 –14		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Currer	nt	$egin{array}{c cccc} V_{DS} = & 16 \ V, & V_{GS} = 0 \ V \\ V_{DS} = & -16 \ V, & V_{GS} = 0 \ V \\ \end{array}$				1 -1	μΑ
I <sub>GSSF</sub> /I <sub>GSSR</sub>	Gate-Body Leakage, Forward		$V_{GS} = \pm 12 \text{ V},  V_{DS} = 0 \text{ V}$				±100	nA
I <sub>GSSF</sub> /I <sub>GSSR</sub>	Gate-Body Leakage, Reverse		$V_{GS} = \pm 12V$ , $V_{DS} = 0 V$				±100	nA
On Char	acteristics (Note 2)							
V <sub>GS(th)</sub>	Gate Threshold Voltage	Q1	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$ 0.6 1.1			1.1	1.5	V
		Q2	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-(	0.6	-1.2	-1.5	
$\Delta V_{GS(th)}$	Gate Threshold Voltage	Q1	I <sub>D</sub> = 250 μA,Ref. To 25°C			-2.8		mV/°C
ΔT <sub>J</sub>	Temperature Coefficient	Q2	$I_D = -250 \mu\text{A,Ref. to } 25^{\circ}\text{C}$			3	000	_
$R_{DS(on)}$	Static Drain–Source	Q1	$V_{GS} = 4.5 \text{ V},  I_{D} = 0.7 \text{ A}$ $V_{GS} = 2.5 \text{ V},  I_{D} = 0.6 \text{ A}$			180	300 400	mΩ
	On–Resistance		$V_{GS} = 2.5 \text{ V},  I_D = 0.7 \text{ A}, T_J = 125^{\circ}$	С		293 247	442	
		Q2	$V_{GS} = -4.5 \text{ V}, I_D = -0.6 \text{ A}$	_		300	420	
		QZ	$V_{GS} = -2.5 \text{ V}, I_D = -0.5 \text{ A}$			470	630	
			$V_{GS}=-4.5 \text{ V}, I_D=-0.6 \text{ A}, T_J=125^\circ$	C C		400	700	
<b>g</b> FS	Forward Transconductance	Q1	$V_{DS} = 5 \text{ V}$ $I_{D} = 0.7 \text{ A}$			2.8		S
		Q2	$V_{DS} = -5 \text{ V}$ $I_{D} = -0.6 \text{A}$			1.8		
I <sub>D(on)</sub> O	On–State Drain Current		$V_{GS} = 4.5 \text{ V},  V_{DS} = 5 \text{ V}$		1	1.0		Α
	On-State Diam Current	Q1						^
		Q2	$V_{GS} = -4.5 \text{ V}, \ V_{DS} = -5 \text{ V}$	-	-2			
Dynamic	: Characteristics							
C <sub>iss</sub>	Input Capacitance	Q1	V <sub>DS</sub> =10 V, V <sub>GS</sub> = 0 V, f=1.0MHz			113		pF
		Q2	$V_{DS}$ =-10 V, V $_{GS}$ = 0 V, f=1.0MH	z		114		
Coss	Output Capacitance	Q1	V <sub>DS</sub> =10 V, V <sub>GS</sub> = 0 V, f=1.0MHz			34		pF
		Q2	V <sub>DS</sub> =-10 V, V <sub>GS</sub> = 0 V, f=1.0MH	z		24		'
C <sub>rss</sub>	Reverse Transfer Capacitance	Q1	$V_{DS}$ =10 V, V $_{GS}$ = 0 V, f=1.0MHz			16		pF
Orss	Neverse Transfer Capacitance	Q2	$V_{DS}$ =-10 V, V $_{GS}$ = 0 V, f=1.0MH			9		PΓ
<b>.</b>		Q2	VDS=-10 V, V GS= 0 V, I=1.0WIT			9		
Switchin	g Characteristics (Note 2)		1			1	1	Т
$t_{d(on)}$	Turn-On Delay Time	Q1	For <b>Q1</b> :			5	10	ns
		Q2	$V_{DS} = 10 \text{ V},  I_{D} = 1 \text{ A}$			5.5	11	
$t_r$	Turn-On Rise Time	Q1	$V_{GS}$ = 4.5 V, $R_{GEN}$ = 6 $\Omega$			7	15	ns
		Q2	For <b>Q2</b> :			14	25	
$t_{\text{d(off)}} \\$	Turn-Off Delay Time	Q1	$V_{DS} = -10 \text{ V},  I_{D} = -1 \text{ A}$			9	18	ns
		Q2	$V_{GS}$ = -4.5 V, $R_{GEN}$ = 6 $\Omega$			6	12	
$t_{f}$	Turn-Off Fall Time	Q1				1.5	3	ns
		Q2				1.7	3.4	
$Q_g$	Total Gate Charge	Q1	For <b>Q1</b> :			1.1	1.5	nC
		Q2	$V_{DS} = 10 \text{ V},  I_{D} = 0.7 \text{ A}$			1.4	2	
Q <sub>qs</sub> Gate–So	Gate-Source Charge	Q1	$V_{GS}$ = 4.5 V, $R_{GEN}$ = 6 $\Omega$			0.24		nC
		Q2	For <b>Q2</b> :			0.3		
Q <sub>gd</sub>	Gate-Drain Charge	Q1	$V_{DS} = -10 \text{ V},  I_{D} = -0.6 \text{ A}$ $V_{GS} = -4.5 \text{ V},  R_{GEN} = 6 \Omega$			0.3		nC
J.	I	Q2	VGS4.0 V, INGEN = 0.22			0.4		1

Electri	cai Characteristics		$T_A = 25^{\circ}C$ unless otherwise noted					
Symbol	Parameter		Test Condition	Min	Тур	Max	Units	
Drain-S	ource Diode Characteris	tics a	nd Maximum Rating	gs				
Is	Maximum Continuous Drain-So	ource [	Diode Forward Current Q1				0.25	Α
							-0.25	
V <sub>SD</sub> Drain–Source Diode Forward			$V_{GS} = 0 \text{ V}, I_{S} = 0.25 \text{ A}$	(Note 2)		0.74	1.2	V
\   \	Voltage	Q2	$V_{GS} = 0 \text{ V}, I_{S} = -0.25 \text{ A}$	(Note 2)		-0.77	-1.2	

**2.** Pulse Test: Pulse Width <  $300\mu$ s, Duty Cycle < 2.0%

<sup>1.</sup> R<sub>BJA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta,JC}$  is guaranteed by design while  $R_{\theta,JA}$  is determined by the user's board design.  $R_{\theta,JA} = 415^{\circ}\text{C/W}$  when mounted on a minimum pad of FR-4 PCB in a still air environment.

## **Typical Characteristics: N-Channel**

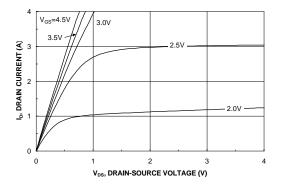


Figure 1. On-Region Characteristics.

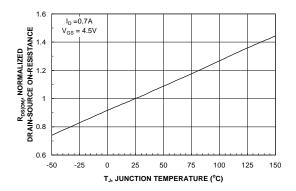


Figure 3. On-Resistance Variation with Temperature.

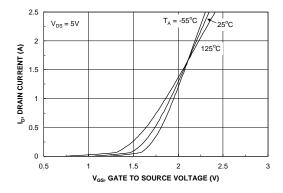


Figure 5. Transfer Characteristics.

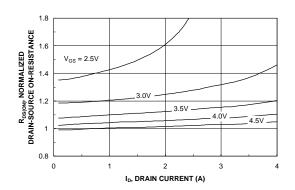


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

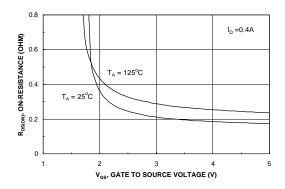


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

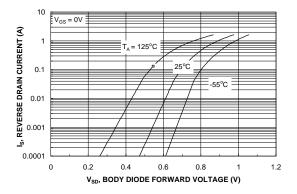


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

# **Typical Characteristics: N-Channel**

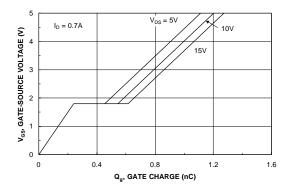


Figure 7. Gate Charge Characteristics.

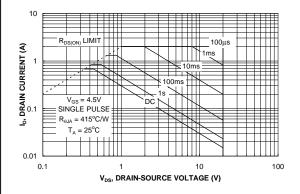


Figure 9. Maximum Safe Operating Area.

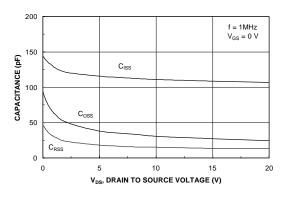


Figure 8. Capacitance Characteristics.

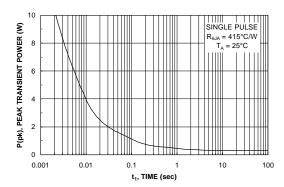


Figure 10. Single Pulse Maximum Power Dissipation.

## **Typical Characteristics: P-Channel**

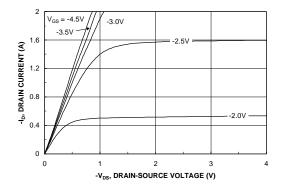


Figure 11. On-Region Characteristics.

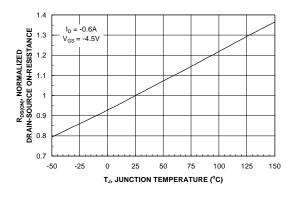


Figure 13. On-Resistance Variation with Temperature.

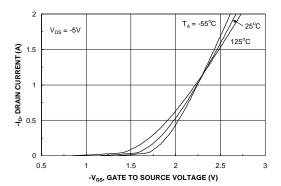


Figure 15. Transfer Characteristics.

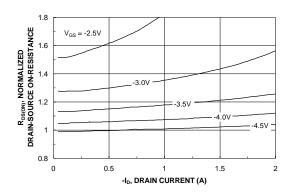


Figure 12. On-Resistance Variation with Drain Current and Gate Voltage.

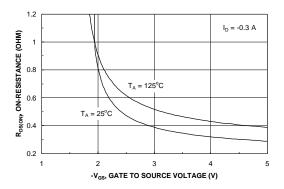


Figure 14. On-Resistance Variation with Gate-to-Source Voltage.

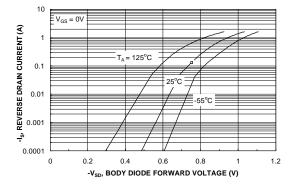
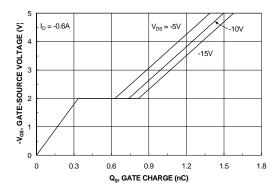


Figure 16. Body Diode Forward Voltage Variation with Source Current and Temperature.

## **Typical Characteristics: P-Channel**



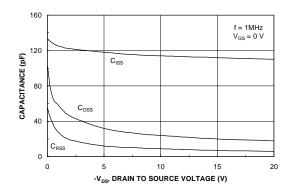


Figure 17. Gate Charge Characteristics.

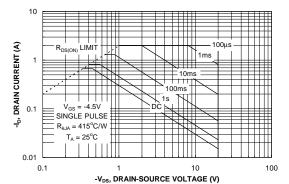


Figure 18. Capacitance Characteristics.

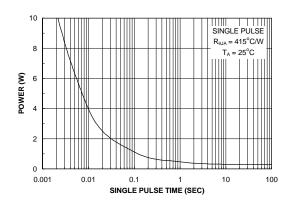


Figure 19. Maximum Safe Operating Area.

Figure 20. Single Pulse Maximum Power Dissipation.

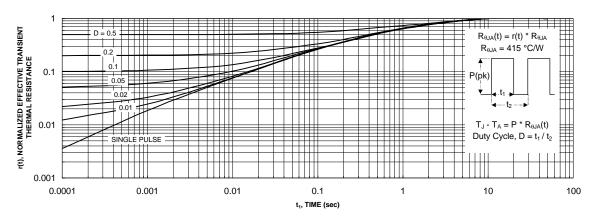


Figure 21. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1. Transient thermal response will change depending on the circuit board design.

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